Amendments to the Specification:

Please replace paragraph [0085] of the published application
(note: **the originally filed application did not contain this
error found in the publication**), with the following paragraph:
--In the example considered, two individual tests are carried
out by the ~~DIST~~ BIST module, and test result data and an item
of test status data are generated for each individual test.
These items of data each include one bit. Test result data
with the value 0 indicates that the relevant test was not
passed. Test result data with the value 1 indicates that the
relevant test was passed successfully. Test status data with
the value 0 indicates that the relevant test has not yet
finished, and test status data with the value 1 indicates that
the relevant test has finished.--

Please replace the paragraph beginning on page 40, line 1,
with the following paragraph:
--In particular, each wafer carrier contains a contact-making
device WK, the contact-making devices of all the wafer
carriers are connected to a common control device CM that
provides and generates the necessary voltages and signals. The
control device CM is either transported together with the ~~text~~
test box, or is connected to the contact-making devices WK via
lines which are so long that the test box TB and the control
device CM can be moved relative to each other. The
simultaneous testing of the integrated circuits produced on a

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plurality of wafers makes it possible to reduce to a minimum

the number of control devices CM to be provided for this

purpose.--